## WHAT IS CLAIMED IS:

| 1  | 1. A thin film transistor array substrate comprising:                    |
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| 2  | an insulating substrate;   |
| 3  | a first metallic pattern formed on said insulting substrate;             |
| 4  | an insulating film provided on said first metallic pattern;              |
| 5  | a semiconductor pattern provided on said insulating film;                |
| 6  | and  |
| 7  | a second metallic pattern provided on said semiconductor                 |
| 8  | pattern;   |
| 9  | wherein said second metallic pattern is surrounded by said               |
| 10 | semiconductor pattern.   |
|    |  |
| 1  | 2. The thin film transistor array substrate according to claim           |
| 2  | 1, wherein at the source electrode part in a pixel region, a part of the |
| 3  | semiconductor pattern surrounding the source electrode exists only on    |
| 4  | the first metallic pattern.  |
|    |  |
| 1  | 3. A thin film transistor array substrate comprising:                    |
| 2  | an insulating substrate;   |
| 3  | a gate line formed on said insulating substrate;                         |
| 4  | a gate insulating film provided on said gate line;                       |
| 5  | a semiconductor layer provided on said gate insulating film;             |
| 6  | a source line, a source electrode and a drain electrode                  |
| 7  | provided on said semiconductor layer;                                    |
| 8  | and  |
| ^  | a nivel electrode formed an said drain electrode                         |

| 10 | wherein said source line, said source electrode and said          |
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| 11 | drain electrode are surrounded by said semiconductor layer;       |
| 12 | wherein said pixel electrode is directly in contact with at least |
| 13 | a portion of said drain electrode.                                |

| 1  | 4. A thin film transistor array substrate comprising:                    |
|----|--|
| 2  | an insulating substrate;   |
| 3  | a gate line formed on said insulating substrate;                         |
| 4  | a gate insulating film provided on said gate line;                       |
| 5  | a semiconductor layer provided on said gate insulating film;             |
| 6  | a source line, a source electrode and a drain electrode                  |
| 7  | provided on said semiconductor layer;                                    |
| 8  | an inter-layer insulating film formed on said source line, said          |
| 9  | source electrode and said drain electrode; and                           |
| 10 | a pixel electrode formed on said inter-layer insulating film;            |
| 11 | wherein said source line, said source electrode and said                 |
| 12 | drain electrode are surrounded by said semiconductor layer;              |
| 13 | wherein said inter-layer insulating film is provided with a              |
| 14 | first contact hole, a second contact hole and a third contact hole, said |
| 15 | first contact hole penetrating said inter-layer insulating film to reach |
| 16 | said drain electrode, said second contact hole extending to said source  |
| 17 | line through said inter-layer insulating film, said third contact hole   |
| 18 | extending to said gate line through said gate insulating film and said   |
| 19 | inter-layer insulating film; and   |
| 20 | wherein said first contact hole, said second contact hole and            |
| 21 | said third contact hole are covered with a pattern made of a material of |
| 99 | said nivel electrode   |

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| 1 | 5. The thin film transistor array substrate according to claim           |
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| 2 | 4, wherein at the source electrode part in a pixel region, a part of the |
| 3 | semiconductor pattern surrounding the source electrode exists only on    |
| 4 | the gate line.   |
|   |  |

6. Method for manufacturing a thin film transistor array substrate comprising steps of:

a first photolithography and etching step for forming a gate line;

depositing a gate insulating film, a semiconductor film, an ohmic contact film and a first metallic thin film;

a second photolithography step for forming a resist pattern of a source line, a source electrode, and a drain electrode;

forming a region of said resit pattern serving as a semiconductor active layer in the thin film transistor in such a manner that thickness of said resist pattern in at least said region serving as a semiconductor active layer is smaller than that in said source line, said source electrode and said drain electrode in the second photolithography process after depositing a second metallic film;

etching said second metallic film to form the source line, the source electrode and the drain electrode;

removing the resist in the region serving as a semiconductor active layer and etching said second metallic film to remove said second metallic film on said region serving as a semiconductor active layer, removing said ohmic contact film on said region serving as a semiconductor active layer;

a third photolithography and etching step of patterning the

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| 23 | gate insulating film for forming a contact hole extending to the gate line; |
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| 24 | depositing a conducting film; and   |
| 25 | a fourth photolithography and etching step of forming a pixel               |
| 26 | electrode in such a manner that said pixel electrode is connected with      |
| 27 | said drain electrode.   |

- 7. Method for manufacturing a thin film transistor array substrate comprising steps of:
- a first photolithography and etching step for forming a gate line;
- depositing a gate insulating film, a semiconductor film, an ohmic contact film and a first metallic thin film;
  - a second photolithography step for forming a resist pattern of a source line, a source electrode, and a drain electrode;

forming a region of said resit pattern serving as a semiconductor active layer in the thin film transistor in such a manner that thickness of said resist pattern in at least said region serving as a semiconductor active layer is smaller than that in said source line, said source electrode and said drain electrode in the second photolithography process after depositing a second metallic film;

etching said second metallic film to form the source line, the source electrode and the drain electrode;

removing the resist in the region serving as a semiconductor active layer and etching said second metallic film to remove said second metallic film on said region serving as a semiconductor active layer, removing said ohmic contact film on said region serving as a semiconductor active layer;

| 22          | a third photolithography and etching step of patterning the                 |
|-------------|---|
| 23          | gate insulating film for forming a contact hole extending to the gate line; |
| 24          | depositing a conducting film; and   |
| 25          | a fourth photolithography and etching step of forming a pixel               |
| 26          | electrode in such a manner that said pixel electrode is connected with      |
| 27          | said drain electrode, forming a source terminal in such a manner that       |
| 28          | said source terminal is connected with said source line, forming a gate     |
| 29          | terminal in such a manner that said gate terminal is connected with said    |
| 30          | gate line.  |
|             |   |
| 1           | 8. Method for manufacturing a thin film transistor array                    |
| 2           | substrate comprising steps of:  |
| 3           | a first photolithography and etching step for forming a gate                |
| 4           | line;   |
| 5           | depositing a gate insulating film, a semiconductor film, an                 |
| 6           | ohmic contact film and a first metallic thin film;                          |
| 7           | a second photolithography step for forming a resist pattern of              |
| 8           | a source line, a source electrode, and a drain electrode;                   |
| 9           | forming a region of said resit pattern serving as a                         |
| 10          | semiconductor active layer in the thin film transistor in such a manner     |
| 11          | that thickness of said resist pattern in at least said region serving as a  |
| 12          | semiconductor active layer is smaller than that in said source line, said   |
| 13          | source electrode and said drain electrode in the second                     |
| 14          | photolithography process after depositing a second metallic film;           |
| <b>15</b> . | etching said second metallic film to form the source line, the              |
| 16          | source electrode and the drain electrode;                                   |

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serving as a semiconductor active layer and etching said second metallic film to remove said second metallic film on said region serving as a semiconductor active layer, removing said ohmic contact film on said region serving as a semiconductor active layer;

depositing an inter-layer insulating film;

a third photolithography and etching step of patterning said gate insulating film and said inter-layer insulating film to form a first contact hole extending to said drain electrode, a second contact hole extending to said source line and a third contact hole extending to said gate line;

depositing a conducting film; and

a fourth photolithography and etching step of forming a pixel electrode in such a manner that said pixel electrode is connected with said drain electrode via said first contact hole, forming a source terminal in such a manner that said source terminal is connected with said source line via said second contact hole, forming a gate terminal in such a manner that said gate terminal is connected with said gate line via said third contact hole.

- 9. Method for manufacturing a thin film transistor array substrate comprising steps of:
- a first photolithography and etching step for forming a gate line and a conversion line for a source line;
- depositing a gate insulating film, a semiconductor film, an ohmic contact film and a first metallic thin film;
- a second photolithography step for forming a resist pattern of a source line, a source electrode, and a drain electrode;

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forming a region of said resit pattern serving as a 9 semiconductor active layer in the thin film transistor in such a manner 10 that thickness of said resist pattern in at least said region serving as a 11 semiconductor active layer is smaller than that in said source line, said 12 electrode and said drain electrode in the second source 13 photolithography process after depositing a second metallic film; 14

etching said second metallic film to form the source line, the source electrode and the drain electrode;

removing the resist in the region serving as a semiconductor active layer and etching said second metallic film to remove said second metallic film on said region serving as a semiconductor active layer, removing said ohmic contact film on said region serving as a semiconductor active layer;

a third photolithography and etching step of patterning said gate insulating film to form a first contact hole extending to said drain electrode, a second contact hole extending to said source line, a third contact hole extending to said gate line, a fourth contact hole extending to gate line material of said conversion line and a fifth contact hole extending to the source line;

depositing a conducting film; and

a fourth photolithography and etching step of forming a pixel electrode in such a manner that said pixel electrode is connected with said drain electrode via said first contact hole, forming a source terminal in such a manner that said source terminal is connected with said source line via said second, fourth and fifth contact hole, forming a gate terminal in such a manner that said gate terminal is connected with said gate line via said third contact hole.

| 1   | 10. Method for manufacturing a thin film transistor array                     |
|-----|---|
| 2   | substrate comprising steps of:  |
| 3   | a first photolithography and etching step for forming a gate                  |
| 4   | line and a conversion line for a source line formed of a first metallic film; |
| 5   | depositing a gate insulating film, a semiconductor film, an                   |
| 6   | ohmic contact film and a first metallic thin film;                            |
| 7   | a second photolithography step for forming a resist pattern of                |
| 8   | a source line, a source electrode, and a drain electrode;                     |
| 9   | forming a region of said resit pattern serving as a                           |
| 10  | semiconductor active layer in the thin film transistor in such a manner       |
| 11  | that thickness of said resist pattern in at least said region serving as a    |
| 12  | semiconductor active layer is smaller than that in said source line, said     |
| 13  | source electrode and said drain electrode in the second                       |
| 14  | photolithography process after depositing a second metallic film;             |
| 15  | etching said second metallic film to form the source line, the                |
| 16  | source electrode and the drain electrode;                                     |
| 17  | removing the resist in the region serving as a semiconductor                  |
| 18  | active layer and etching said second metallic film to remove said second      |
| 19  | metallic film on said region serving as a semiconductor active layer,         |
| 20  | removing said ohmic contact film on said region serving as a                  |
| 21  | semiconductor active layer;   |
| 22  | depositing an inter-layer insulating film;                                    |
| 23  | a third photolithography and etching step of patterning said                  |
| 24  | gate insulating film and said inter-layer insulating film to form a first     |
| 25  | contact hole extending to said drain electrode, a second contact hole         |
| 26  | extending to said source line, a third contact hole extending to said gate    |
| 977 | line a fourth contact hale extending to the first metallic film of said       |

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conversion line for the source line and a fifth contact hole extending to said second metallic film;

depositing a conducting film; and

a fourth photolithography and etching step of forming a pixel electrode in such a manner that said pixel electrode is connected with said drain electrode via said first contact hole, forming a source terminal in such a manner that said source terminal is connected with said source line via said second, fourth and fifth contact hole, forming a gate terminal in such a manner that said gate terminal is connected with said gate line via said third contact hole.

- 1 11. A thin film transistor array for a liquid crystal display comprising:
- a gate line/gate electrode comprising a transparent conductive layer and a metallic layer provided on said transparent conductive layer;
- a pixel electrode defined by the same transparent conductive layer as said transparent conductive layer of said gate line/gate electrode; and
- 9 retaining capacitance electrode formed of the same material 10 for an electrode as that for a source line, said retaining capacitance 11 electrode being connected with said pixel electrode;
- wherein said metallic layer provided on said gate line/gate electrode is removed from in a part serving as said pixel electrode.
- 1 12. A thin film transistor array for a liquid crystal display comprising:

| 3  | a gate line/gate electrode and a common line, both of which                 |
|----|---|
| 4  | comprise a transparent conductive layer and a metallic layer provided       |
| 5  | on said transparent conductive layer;                                       |
| 6  | a pixel electrode defined by the same transparent conducive                 |
| 7  | layer as said transparent conductive layer of said gate line/gate           |
| 8  | electrode; and  |
| 9  | a retaining capacitance electrode formed of the same material               |
| ιo | for an electrode as that for a source line, said retaining capacitance      |
| 11 | being connected with pixel electrode;                                       |
| 12 | wherein said metallic layer provided on said gate line/gate                 |
| 13 | electrode is removed from in a part serving as said pixel electrode.        |
|    |   |
| 1  | 13. A thin film transistor array for a liquid crystal display               |
| 2  | comprising:   |
| 3  | a gate line/gate electrode comprising a transparent                         |
| 4  | conductive layer and a metallic layer provided on said transparent          |
| 5  | conductive layer;   |
| 6  | a pixel electrode defined by the same transparent conductive                |
| 7  | layer as said transparent conductive layer of said gate line/gate           |
| 8  | electrode; and  |
| 9  | retaining capacitance electrode formed of the same material                 |
| 10 | for an electrode as that for a source line, said retaining capacitance      |
| 11 | electrode being connected with said pixel electrode;                        |
| 12 | wherein said metallic layer provided on said gate line/gate                 |
| 13 | electrode is removed from in a part serving as said pixel electrode;        |
| 14 | wherein at least a material for said source line located in a               |
| 15 | lowermost layer is the same material as that for said metallic layer of the |

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| 16 | pixel electrode, when a material for said source line has a muti-layered |
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| 17 | structure or said source line per se has a multi-layered structure.      |

| 1      | 14. A thin film transistor array for a liquid crystal display |
|--------|---|
| 2      | comprising:   |
| _<br>3 | a gate line/gate electrode and a common line, both of which   |

a gate line/gate electrode and a common line, both of which comprise a transparent conductive layer and a metallic layer provided on said transparent conductive layer;

a pixel electrode defined by the same transparent conductive layer as said transparent conductive layer of said gate line/gate electrode; and

retaining capacitance electrode formed of the same material for an electrode as that for a source line, said retaining capacitance electrode being connected with said pixel electrode;

wherein said metallic layer provided on said gate line/gate electrode is removed from in a part serving as said pixel electrode;

wherein at least a material for said source line located in a lowermost layer is the same material as that for said metallic layer of the pixel electrode, when a material for said source line has a muti-layered structure or said source line per se has a multi-layered structure

1 15. A thin film transistor array for a liquid crystal display comprising:

a gate line/gate electrode including at least two layers comprising a metallic layer and a transparent conductive layer, said metallic layer being formed on said transparent conductive layer;

a pixel electrode being formed by a transparent conductive

| 7  | layer which is the same as said transparent conductive layer of said gate |
|----|---|
| 8  | line/gate electrode;  |
| 9  | a gate insulating film and a semiconductor layer being                    |
| 10 | formed on at least said gate electrode;                                   |
| 11 | source/drain electrodes being formed in such a manner as to               |
| 12 | contact with said semiconductor layer;                                    |
| 13 | at least an n <sup>+</sup> - Si layer of said semiconductor layer located |
| 14 | between said source/drain electrodes being removed;                       |
| 15 | a retaining capacitance electrode which is formed of a same               |
| 16 | layer as that of said source line;  |
| 17 | a retaining capacitance line including at least two layers                |
| 18 | comprising said metallic layer and said transparent conductive layer      |
| 19 | simultaneously formed with said gate line, wherein a retaining            |
| 20 | capacitance is formed in such a manner that said retaining capacitance    |
| 21 | electrode is opposed to said gate line via said gate insulating film;     |
| 22 | at least said gate insulating film, said semiconductor layer,             |
| 23 | and said metallic layer of said pixel electrode being simultaneously      |
| 24 | formed with said gate line/gate electrode including at least two layers,  |
| 25 | which are located over a light transmitting portion are removed;          |
| 26 | a part of said semiconductor layer being removed in order                 |
| 27 | that adjacent source lines are not short-circuited with said              |
| 28 | semiconductor layer;  |
| 29 | said gate insulating film having such a thickness right under             |
| 30 | said semiconductor layer is larger than that at any other part of said    |
| 31 | gate insulating film.   |

| 2  | comprising:   |
|----|---|
| 3  | a gate line/gate electrode and a common line including two                  |
| 4  | layers comprising a metallic layer and a transparent conductive layer,      |
| 5  | said metallic layer being formed on said transparent conductive layer;      |
| 6  | a pixel electrode being formed by a transparent conductive                  |
| 7  | layer which is the same as said transparent conductive layer of said gate   |
| 8  | line/gate electrode;  |
| 9  | a gate insulating film and a semiconductor layer being                      |
| 10 | formed at least on said gate electrode;                                     |
| 11 | a source/drain electrodes being formed in such a manner as                  |
| 12 | to contact with said semiconductor layer;                                   |
| 13 | at least an n <sup>+</sup> - Si layer of said semiconductor layer being     |
| 14 | located between said source/drain electrodes is removed;                    |
| 15 | a retaining capacitance electrode, which is formed of a same                |
| 16 | layer as said source line, being connected with said pixel electrode;       |
| 17 | a retaining capacitance line including at least two layers                  |
| 18 | comprising metallic layer and said transparent conductive layer             |
| 19 | simultaneously formed with said gate line, wherein a retaining              |
| 20 | capacitance is formed in such a manner that said retaining capacitance      |
| 21 | electrode is opposed to said common line via said gate insulating film;     |
| 22 | at least said gate insulating film, said semiconductor layer,               |
| 23 | and said metallic layer of said pixel electrode simultaneously formed       |
| 24 | with said gate line/gate electrode including at least two layers, which are |
| 25 | located over a light transmitting portion being removed;                    |
| 26 | a part of said semiconductor layer being removed in order                   |
| 27 | that adjacent source lines are not short-circuited with said                |
| 28 | semiconductor layer;  |

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| 29         | said gate insulating film has such a thickness right under                  |
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| 30         | said semiconductor layer being larger than that at any other part of said   |
| 31         | gate insulating film.   |
|            |   |
| 1          | 17. Method for manufacturing a TFT array of liquid crystal                  |
| 2          | display comprising steps of:  |
| 3          | depositing a gate electrode/gate line and a pixel electrode,                |
| 4          | each of said gate electrode/gate line and said pixel electrode including at |
| 5          | least two layers comprising a transparent conductive layer and metallic     |
| 6          | layer provided on said transparent conductive layer, and subsequently       |
| 7          | etching said gate electrode/gate line and said pixel electrode using a      |
| 8          | photoresist having patterns corresponding to said gate electrode/gate       |
| 9          | line and said pixel electrode to form a predetermined patterns;             |
| 10         | forming a gate insulating film and a semiconductor film;                    |
| 11         | exposing said pixel electrode by etching process using said                 |
| 12         | photoresist having patterns;  |
| 13         | removing said metallic layer having at least two layer in said              |
| 14         | exposed pixel electrode by etching process; and                             |
| 15         | forming a drain electrode, a source electrode, and a source                 |
| 16         | line.   |
|            |   |
| 1          | 18. Method for manufacturing a TFT array of liquid crystal                  |
| 2          | display comprising steps of:  |
| . <b>3</b> | depositing a gate electrode/gate line and a pixel electrode,                |
| 4          | each of said gate electrode/gate line and said pixel electrode including at |

layer provided on said transparent conductive layer, and subsequently

least two layers comprising a transparent conductive layer and metallic

| 7        | etching said gate electrode/gate line and said pixel electrode using a      |
|----------|---|
| 8        | photoresist having a patterned shape corresponding to said gate             |
| 9        | electrode/gate line and said pixel electrode to form a predetermined        |
| 10       | patterns;   |
| 11       | forming a gate insulating film and a semiconductor film;                    |
| 12       | exposing said pixel electrode by etching process using said                 |
| 13       | photoresist having patterns;  |
| 14       | forming a metallic layer for a drain electrode, a source                    |
| 15       | electrode, and a source line;   |
| 16       | etching said metallic layer using said photoresist having the               |
| 17       | the predetermined patterns to form said drain electrode, said source        |
| 18       | electrode, and said source line;  |
| 19       | wherein said metallic layer in said exposed pixel electrode                 |
| 20       | having at least two layers.   |
|          |   |
| 1        | 19. Method for manufacturing a TFT array of liquid crystal                  |
| <b>2</b> | display comprising steps of:  |
| 3        | depositing a gate electrode/gate line and a pixel electrode,                |
| 4        | each of said gate electrode/gate line and said pixel electrode including at |
| 5        | least two layers comprising a transparent conductive layer and metallic     |
| 6        | layer provided on said transparent conductive layer, and subsequently       |
| 7        | etching said gate electrode/gate line and said pixel electrode using a      |
| 8        | photoresist having a patterned shape corresponding to said gate             |
| 9        | electrode/gate line and said pixel electrode to form a predetermined        |
| 10       | patterns;   |
| 11       | forming a gate insulating film and a semiconductor film;                    |
| 12       | forming a region (A) where at least of a portion of said                    |

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| 13 | photoresist corresponding to said semiconductor layer to be left has a       |
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| 14 | thickness being larger than any other part of said photoresist, a region     |
| 15 | (C) where at least of a portion of said photoresist corresponding to a light |
| 16 | transmitting part of said pixel electrode to be exposed is removed, and a    |
| 17 | region (B) where any parts other than said region (A) and said region (B)    |
| 18 | having a thickness smaller than that of said semiconductor layer;            |
| 19 | etching said semiconductor layer and said gate insulating                    |
| 20 | film using said photoresist having said thickness in each part to expose     |
| 21 | said pixel electrode;  |
| 22 | removing at least said metallic layer located in upper side of               |
| 23 | said two layers in said exposed pixel electrode by etching process;          |
| 24 | removing said photoresist in said region (B) from upper side                 |
| 25 | while leaving said phoresist in said region (A);                             |
| 26 | removing said photoresit in any part other than that in said                 |
| 27 | region (A); and  |
| 28 | forming a source/drain electrodes.   |

20. Method for manufacturing a TFT array of liquid crystal
display comprising steps of:

depositing a gate electrode/gate line, a pixel electrode and a common line, each of said gate electrode/gate line, said pixel electrode and said common line including at least two layers comprising a transparent conductive layer and a metallic layer provided on said transparent conductive layer;

etching said gate electrode/gate line, said pixel electrode and said common line using a photoresist having a patterned shape corresponding to said gate electrode/gate line, said pixel electrode and

| 11  | said common line to form a predetermined pattern;                            |
|-----|--|
| 12  | forming a gate insulating film and a semiconductor film;                     |
| 13  | forming a region (A) where at least of a portion of said                     |
| 14  | photoresist corresponding to said semiconductor layer to be left has a       |
| 15  | thickness being larger than any other part of said photoresist, a region     |
| 16  | (C) where at least of a portion of said photoresist corresponding to a light |
| 17  | transmitting part of said pixel electrode to be exposed is removed, and a    |
| 18  | region (B) where any parts other than said region (A) and said region (B)    |
| 19  | having a thickness smaller than that of said semiconductor layer;            |
| 20  | etching said semiconductor layer and said gate insulating                    |
| 21  | film using said photoresist having said thickness in each part to expose     |
| 22  | said pixel electrode;  |
| 23  | removing at least said metallic layer located in upper side of               |
| 24  | said two layers in said exposed pixel electrode by etching process;          |
| 25  | removing said photoresist in said region (B) from upper side                 |
| 26  | while leaving said phoresist in said region (A);                             |
| 27  | removing said photoresit in any part other than that in said                 |
| 28  | region (A); and  |
| 29  | forming a source/drain electrodes.   |
|     |  |
| _ 1 | 21. Method for manufacturing a TFT array of liquid crystal                   |
| 2   | display comprising steps of:   |
| 3   | depositing a gate electrode/gate line and a pixel electrode,                 |

least two layers comprising a transparent conductive layer and metallic layer provided on said transparent conductive layer, and subsequently etching said gate electrode/gate line and said pixel electrode using a

each of said gate electrode/gate line and said pixel electrode including at

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| 8  | photoresist having a predetermined patterned shape corresponding to          |
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| 9  | said gate electrode/gate line and said pixel electrode to form a             |
| 10 | predetermined patterns;  |
| 11 | forming a gate insulating film and a semiconductor film;                     |
| 12 | forming a region (A) where at least of a portion of said                     |
| 13 | photoresist corresponding to said semiconductor layer to be left has a       |
| 14 | thickness being larger than any other part of said photoresist, a region     |
| 15 | (C) where at least of a portion of said photoresist corresponding to a light |
| 16 | transmitting part of said pixel electrode to be exposed is removed, and a    |
| 17 | region (B) where any parts other than said region (A) and said region (B)    |
| 18 | having a thickness smaller than that of said semiconductor layer;            |
| 19 | etching said semiconductor layer and said gate insulating                    |
| 20 | film using said photoresist having said thickness in each part to expose     |
| 21 | said pixel electrode;  |
| 22 | removing said photoresist in said region (B) from upper side                 |
| 23 | while leaving said phoresist in said region (A);                             |
| 24 | removing said photoresit in any part other than that in said                 |
| 25 | region (A);  |
| 26 | forming a source/drain electrode made of the same metallic                   |
| 27 | material as that used for an upper layer of said two layers of said gate     |
| 28 | line; and  |
| 29 | removing said source/drain electrode by etching process,                     |
| 30 | while removing said metallic layer located in said upper layer of said two   |
| 21 | layers of said exposed nivel electrode by etching process                    |

22. TFT array substrate for a liquid crystal comprising: source lines and gate lines which are formed in matrix;

| 3              | a pixel electrode for applying voltage to a liquid crystal and              |
|----------------|---|
| 4              | thin film transistors, said pixel electrode being provided in each of parts |
| 5              | in which said source lines are intersected with said gate lines, said pixel |
| 6              | electrode being protected by a passivation film;                            |
| 7              | a gate electrode;   |
| 8              | a gate insulating film formed on said gate electrode;                       |
| 9              | a semiconductor layer film provided on said gate insulating                 |
| 10             | film on a region of said gate electrode, said semiconductor layer being     |
| 11             | formed in such a manner as to contact with said gate insulating film;       |
| 12             | a source electrode, a source line and a drain electrode, each               |
| 13             | of said source electrode, said source line and said drain electrode         |
| 14             | including at least two layers comprising a transparent conductive film      |
| 15             | and a metallic film provided on said transparent conductive layer, said     |
| 16             | transparent conductive film being formed in such a manner as to             |
| 17             | partially contact with said semiconductor layer;                            |
| 18             | wherein said drain electrode is connected with said pixel                   |
| 19             | electrode by said transparent conductive layer per se;                      |
| 20             | wherein said passivation film, and said metallic film and said              |
| 21             | passivation film which are located on said light transmitting part of said  |
| 22             | pixel electrode are removed.  |
|                |   |
| . 1            | 23. Method for manufacturing TFT array substrate for a                      |
| 2              | liquid crystal display comprising steps of:                                 |
| <sub>.</sub> 3 | forming at least a gate insulating film and a semiconductor                 |
| 4              | layer on a gate electrode;  |
| 5              | forming a region (A) in a photoresist having a large thickness              |

to be left as a semiconductor layer, a region (C) where a photoresist is

- 7 removed to expose a gate line, and a region (B) other than said region (A)
- 8 in a photoresist having a thickness smaller than said region (A);
- 9 removing at least gate insulating film and said
- 10 semiconductor layer which are located on said gate line by subjecting
- 11 said gate insulating film and said semiconductor layer to etching
- 12 process using a photoresist having different thickness to partially
- 13 expose said gate electrode;
- reducing the thickness of said photoresist, and subsequently
- 15 removing said photoresist in said region (B) while leaving said
- photoresist in said region (A); and
- 17 removing said semiconductor layer located in a part other
- 18 than said region (A).
- 1 24. Method for manufacturing a TFT array substrate
- 2 comprising steps of:
- depositing a conductive material for a gate electrode/gate
- 4 line;
- 5 etching said deposited conductive material using a
- 6 photoresist having patterned shape corresponding to said gate electrode
- 7 and said gate line to form a predetermined patterns;
- 8 forming a gate insulating film and a semiconductor layer;
- 9 forming a region (A) in a photoresist having a large thickness
- to be left as a semiconductor layer, a region (C) where a photoresist is
- removed to expose a gate line, and a region (B) other than said region (A)
- in a photoresist having a thickness smaller than said region (A);
- removing at least gate insulating film and said
- 14 semiconductor layer which are located on said gate line by subjecting

| 15  | said gate insulating film and said semiconductor layer to etching    |
|-----|--|
| 16  | process using a photoresist having the above-mentioned shape to      |
| 17. | expose at least a part of said gate electrode;                       |
| 18  | removing said photoresist in said region (B) while leaving said      |
| 19  | photoresist in said region (A);                                      |
| 20  | removing said semiconductor layer located in a part other            |
| 21  | than said region (A);  |
| 22  | forming a source/drain electrodes using a photoresist having         |
| 23  | a patterned shape corresponding to said source/drain electrodes in a |
| 24  | transparent conductive layer formed in such a manner as to partially |
| 25  | contact with said semiconductor layer and a metallic layer formed on |
| 26  | said transparent conductive layer;                                   |
| 27  | forming a passivation film;  |
| 28  | removing at least a light transmitting part of said passivation      |
| 29  | film over a pixel electrode; and                                     |
| 30  | forming a pixel electrode by removing said metallic layer on         |
| 31  | said transparent conductive layer from said removed passivation film |
| 32  | formed on said pixel electrode.                                      |

25. The thin film transistor array substrate according to any one of claims 1, 12, 13, 14, 15, 16 or 22, wherein a semiconductor pattern is formed to have a region surrounding a thin film transistor and a region surrounding a source electrode and at least a part of a source line, and at the source electrode part in a pixel region, a part of the semiconductor pattern surrounding the source electrode exists only on a gate line.

- 26. The method of manufacturing a thin film transistor array 1 substrate according to any one of claims 17, 18, 19, 20, 21, 23 or 24 2 3 wherein a semiconductor pattern is formed to have a region surrounding a thin film transistor and a region surrounding a source electrode and at 4 least a part of a source line, and at the source electrode part in a pixel 5 region, said semiconductor pattern is formed so that a part of the 6 7 semiconductor pattern surrounding the source electrode exists only on a gate line. 8
- 27. A liquid crystal display apparatus comprising a thin film transistor array substrate manufactured by the method according to any one of claims 6, 7, 8, 9, 10, 17, 18, 19, 20, 21, 23 or 24.
- 28. A liquid crystal display apparatus comprising a thin film transistor array substrate according to any one of claims 1, 2, 3, 4, 5, 8, 11, 12, 13, 14, 15, 16 or 22.